



National
Semiconductor*

Discrete POWER & Signal
Technologies

Pro Electron Surface Mount Bipolar Devices

Device No. (SOT-23 Mark)	Case Style	V _{CE(SAT)} V _{CB0} (V) Min	V _{CEO} (V) Min	V _{EBO} (V) Min	I _{CE(SAT)} I _{CB0} (nA) Max	H _{FE} h _{FE} Min Max	I _C & V _{CE} (mA) (V)	V _{CE(SAT)} (V) Max	V _{BE(SAT)} V _{BE(ON)} (V) Min Max	I _C (mA) Min Max	C _{ob} (pF) Max	f _T (MHz) Min Max	I _C (mA) Min Max	NF (dB) Max	Test Conditions	Process No.
BC807-16 (5A)	TO-236 (49)	50*	45	5	100 20	100 40	100 500	1	0.7	500		100	10			78 (6-9)
BC807-25 (5B)	TO-236 (49)	50*	45	5	100 20	160 40	100 500	1	0.7	500		100	10			78 (6-9)
BC807-40 (5C)	TO-236 (49)	50*	45	5	100 20	250 40	100 500	1	0.7	500		100	10			78 (6-9)
BC817-25 (6B)	TO-236 (49)	30*	25	5	100 20	160 40	100 500	1	0.7	500		200	10			38 (6-13)
BC817-40 (6C)	TO-236 (49)	30*	25	5	100 20	250 40	100 500	1	0.7	500		200	10			38 (6-13)
BC818-25 (6F)	TO-236 (49)	30*	25	5	100 20	160 40	100 500	1	0.7	500		200	10			38
BC818-40 (6G)	TO-236 (49)	30*	25	5	100 20	250 40	100 500	1	0.7	500		200	10			38
BC846A (1A)	TO-236 (49)	80*	65	6	15 30	110 220	2 5	5 5	0.25 0.6	10 100	4.5	100	10	10	(Note 1)	07 (6-19)
BC846B (1B)	TO-236 (49)	80*	65	6	15 30	200 450	2 5	5 5	0.25 0.6	10 100	4.5	100	10	10	(Note 1)	07 (6-19)
BC847A (1E)	TO-236 (49)	50*	45	6	15 30	110 220	2 5	5 5	0.25 0.6	10 100	4.5	100	10	10	(Note 1)	07 (6-19)
BC847B (1F)	TO-236 (49)	50*	45	6	15 30	200 450	2 5	5 5	0.25 0.6	10 100	4.5	100	10	10	(Note 1)	07 (6-19)
BC847C (1G)	TO-236 (49)	50*	45	6	15 30	420 800	2 5	5 5	0.25 0.6	10 100	4.5	100	10	10	(Note 1)	07 (6-19)

NOTE: National preferred device for each process in bold. Number shown in parentheses indicates location (section-page) of device datasheet.

Pro Electron Series

Pro Electron Surface Mount Bipolar Devices (continued)

Device No. (SOT-23 Mark)	Case Style	V_{CES}^* V_{CBO} (V) Min	V_{CEO} (V) Min	V_{EBO} (V) Min	I_{CES}^* I_{CBO} (mA) Max	V_{CB} (V)	H_{FE} h_{fe} Min Max	I_C & V_{CE} (mA) (V)	$V_{CE(SAT)}$ (V) Max	$V_{BE(SAT)}$ $V_{BE(ON)}$ (V) Min Max	I_C (mA) @ Min Max	C_{ob} (pF) Max	f_T (MHz) Min Max	I_C (mA) @ Min Max	NF (dB) Max	Test Conditions	Process No.
BC848A (1J.)	TO-236 (49)	30	30	5	15	30	110 220	2 5	0.25 0.6		10 100				10	(Note 1)	10
BC848B (1K.)	TO-236 (49)	30	30	5	15	30	200 450	2 5	0.25 0.6		10 100				10	(Note 1)	10
BC848C (1L.)	TO-236 (49)	30	30	5	15	30	420 800	2 5	0.25 0.6		10 100				10	(Note 1)	10
BC849C (2C.)	TO-236 (49)	30	30	5	15	30	420 800	2 5	0.25 0.6		10 100				4	(Note 1)	10
BC850B (2F.)	TO-236 (49)	50	45	5	15	30	200 450	2 5	0.25 0.6		10 100					(Note 1)	10
BC850C (2G.)	TO-236 (49)	50	45	5	15	30	420 800	2 5	0.25 0.6		10 100					(Note 1)	10
BC856B (3B.)	TO-236 (49)	80	65	5	15	30	220 475	2 5	0.3 0.65		10 100				10	(Note 1)	69
BC857A (3E.)	TO-236 (49)	50	45	5	15	30	125 250	2 5	0.3 0.65	0.82*	10 100	4.5	100	10	10	(Note 1)	68 (6-24)
BC857B (3F.)	TO-236 (49)	50	45	5	15	30	220 475	2 5	0.3 0.65	0.82*	10 100	4.5	100	10	10	(Note 1)	68 (6-24)
BC857C (3G.)	TO-236 (49)	50	45	5	15	30	420 800	2 5	0.3 0.65	0.82*	10 100	4.5	100	10	10	(Note 1)	68 (6-24)
BC858A (3L.)	TO-236 (49)	30	30	5	15	30	125 250	2 5	0.3 0.65	0.82*	10 100				10	(Note 1)	68
BC858B (3K.)	TO-236 (49)	30	30	5	15	30	220 475	2 5	0.3 0.65	0.82*	10 100				10	(Note 1)	68
BC858C (3L.)	TO-236 (49)	30	30	5	15	30	420 800	2 5	0.3 0.65	0.82*	10 100				10	(Note 1)	62
BC859B (4B.)	TO-236 (49)	30	30	5	15	30	220 475	2 5	0.65	0.82*	100				4	(Note 1)	68

NOTE: National preferred device for each process in bold. Number shown in parentheses indicates location (section-page) of device datasheet.

Pro Electron Surface Mount Bipolar Devices (continued)

Device No. (SOT-23 Mark)	Case Style	V_{CES}^* V_{CBO} (V) Min	V_{CEO} (V) Min	V_{EBO} (V) Min	I_{CES}^* I_{CBO} (mA) Max	V_{CB} (V) @ Max	H_{FE} h_{fe} Min Max	I_C & V_{CE} (mA) (V) 2 5	$V_{CE(SAT)}$ (V) Max	$V_{BE(SAT)}$ $V_{BE(ON)}$ (V) Min Max	I_C (mA) @ Max	C_{ob} (pF) Max	f_T (MHz) Min Max	I_C (mA) @ Max	NF (dB) Max	Test Conditions	Process No.
BC859C (4C)	TO-236 (49)	30	30	5	15	30	420 800	2 5	0.65		100				4	(Note 1)	68
BC960C (4G)	TO-236 (49)	50	45	5	15	30	420 800	2 5	0.3 0.65		10 100				3	(Note 1)	68
BCP52	TO-261 (47)	60	60	5	100	30	25 40	5 2 150 2	0.5	*1	500						78 (6-28)
BCP53	TO-261 (47)	100	80	5	100	30	25 40	5 2 150 2	0.5	*1	500						78
BCP54	TO-261 (47)	45	45	5	100	30	25 40	5 2 150 2	0.5	*1	500						38 (6-32)
BCP55	TO-261 (47)	60	60	5	100	30	25 40	5 2 150 2	0.5	*1	500						38
BCP56	TO-261 (47)	100	80	5	100	30	25 40	5 2 150 2	0.5	*1	500						38
BCV26 (FD)	TO-236 (49)	40	30	10	100	30	4,000 10,000 20,000	1 5 10 5 100 5	1	1.5	100						61 (6-35)
BCV27 (FF)	TO-236 (49)	40	30	10	100	30	4,000 10,000 20,000	1 5 10 5 100 5	1	1.5	100						05 (6-39)
BCV71 (K7)	TO-236 (49)	80	60	5	100	20	110	220 2 5	0.25		10				10	(Note 1)	10
BCV72 (K8)	TO-236 (49)	80	60	5	100	20	200	450 2 5	0.25		10				10	(Note 1)	10
BCW30 (C2)	TO-236 (49)	32	32	5	100	32	215	0.01 5 2 5	0.3		10				10	(Note 1)	68
BCW31 (D1)	TO-236 (49)	32	32	5	100	32	150	0.01 5 2 5	0.25		10				10	(Note 1)	10

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Pro Electron Surface Mount Bipolar Devices (continued)

Device No. (SOT-23 Mark)	Case Style	V _{CES} [*] V _{CBO} (V) Min	V _{CEO} (V) Min	V _{EBO} (V) Min	I _{CES} [*] I _{CBO} (nA) Max	V _{CB} @ (V) Max	H _{FE} h _{FE} Min Max	I _C & V _{CE} @ (mA) (V) Min Max	V _{CE(SAT)} (V) Max	V _{BE(SAT)} V _{BE(ON)} (V) Min Max	I _C (mA) Min Max	C _{ob} (pF) Max	f _T (MHz) Min Max	I _C (mA) Min Max	t _(on) (ns) Max	NF (dB) Max	Test Conditions	Process No.
BCW32 (D2)	TO-236 (49)	32	32	5	100	32	200 420	0.01 2	5 5	0.25	10					10	(Note 1)	10
BCW33 (D3)	TO-236 (49)	32	32	5	100	32	450 800	0.01 2	5 5	0.25	10					10	(Note 1)	10
BCW60A (AA)	TO-236 (49)	32*	32	5	20	32	50 120	50 2	1 5	0.35	0.6 0.85	50		125	10	6	(Note 1)	10
BCW61A (BA)	TO-236 (49)	32*	32	5	20	32	50 120	50 2	1 5	0.25	0.6 0.85	50				6	(Note 1)	68
BCW61B (BB)	TO-236 (49)	32*	32	5	20	32	80 140	50 2	1 5	0.25	0.6 0.85	50				6	(Note 1)	68
BCW61C (BC)	TO-236 (49)	32*	32	5	20	32	100 250	50 2	1 5	0.25	0.6 0.85	50				6	(Note 1)	68
BCW65C (ED)	TO-236 (49)	60	32	5	20*	32	80 180 250 50	0.1 10 100 500	10 1 1 1	0.7 0.3	2 500 100	12	100	20	400	10	(Note 1) (Note 7)	19 (6-45)
BCW68G (DG)	TO-236 (49)	60	45	5	20*	45	120 160 60	10 100 300	1 1 1	1.5	2 500 300	18	100	20		10	(Note 1)	63 (6-50)
BCW69 (H1)	TO-236 (49)	50	45	5	100	20	120	260	2	0.3	10					10	(Note 1)	68
BCW71 (K1)	TO-236 (49)	50	45	5	100	20	110	220	2	0.25	10	4				10		10 (6-55)
BCW89 (H3)	TO-236 (49)	80	60	5	100	20	120	260	2	0.3	10					10	(Note 1)	68
BCX17 (T1)	TO-236 (49)	50*	45	5	100	20	100 70 40	600 300 500	1 1 1	0.62	500							67

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Pro Electron Surface Mount Bipolar Devices (continued)

Device No. (SOT-23 Mark)	Case Style	V _{CE} [*] V _{CB} (V) Min	V _{CEO} (V) Min	V _{EBO} (V) Min	I _{CE} [*] I _{CB} (nA) Max	V _{CB} (V)	H _{FE} h _{FE} @ I _C & V _{CE} (mA) (V)	V _{CE(SAT)} (V) Max	V _{BE(SAT)} V _{BE(ON)} (V) Min Max	I _C (mA) Max	C _{ob} (pF) Max	f _T (MHz) @ I _C (mA) Min	t _(off) (ns) Max	NF (dB) Max	Test Conditions	Process No.
BCX18 (T2)	TO-236 (49)	30*	25	5	100	20	100 600 70 40 300 500 1	0.62	500	500						67
BCX19 (U1)	TO-236 (49)	50*	45	5	100	20	100 600 70 40 300 500 1	0.62	1.2 500	500						12
BCX20 (U2)	TO-236 (49)	30*	25	5	100	20	100 600 70 40 300 500 1	0.62	1.2 500	500						12
BCX70G (AG)	TO-236 (49)	45	45	5	20	32	120 220 60 2	0.55	0.7 1.05 50	50	4.5	125	800	6	(Note 2) (Note 3)	10
BCX70H (AH)	TO-236 (49)	45	45	5	20	32	180 310 70 20 50 0.01 5	0.55	0.7 1.05 50	50	4.5	125	800	6	(Note 2) (Note 3)	10
BCX70J (AJ)	TO-236 (49)	45	45	5	20	32	250 460 90 40 50 0.01 5	0.55	0.7 1.05 50	50	4.5	125	800	6	(Note 2) (Note 3)	10
BCX71G (BG)	TO-236 (49)	45	45	5	20	32	120 220 60 2	0.55	0.7 1.05 50	50	4.5	125	800	6	(Note 2) (Note 3)	68
BCX71J (BJ)	TO-236 (49)	45	45	5	20	32	250 460 90 40 50 0.01 5	0.55	0.7 1.05 50	50	4.5	125	800	6	(Note 2) (Note 3)	68
BCX71K (BK)	TO-236 (49)	45*	45	5	20*	32	380 630 110 100 2 50 0.01 5	0.55 0.25	1.05 0.85 50 10	50 10	6	125 10	800	6	(Note 2) (Note 3)	68 (6-59)
BSR13 (U7)	TO-236 (49)	60	30	5	30	50	35 50 75 100 50 30 0.1 1 10 10 10 150 150 500 10 10	0.4	1.3 2.6 150 500	150 500	8	250 20				19

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Pro Electron Surface Mount Bipolar Devices (continued)

Device No. (SOT-23 Mark)	Case Style	V _{CES} ⁺ V _{CB0} (V) Min	V _{CEO} (V) Min	V _{EBO} (V) Min	I _{CES} ⁺ I _{CB0} (nA) Max	H _{FE} h _{fe} @ I _c & V _{CE} (mA) Min Max	V _{CE(SAT)} (V) Max	V _{BE(SAT)} V _{BE(ON)} (V) Min Max	I _c (mA) @ I _c Max	C _{ob} (pF) Max	f _T (MHz) @ I _c Min Max	t _(off) (ns) Max	NF (dB) Max	Test Conditions	Process No.
BSR14 (U8)	TO-236 (49)	75	40	6	10	35 50 75 100 50 40	0.1 1 10 150 150 500	10 10 10 10 1 10	0.6 1.2 2	150 500	8	300 20			19
BSR15 (T7)	TO-236 (49)	60	40	5	20	35 50 75 100 30	0.1 1 10 150 500	10 10 10 10 10	0.4 1.3 2.6	150 500	8	200 50		(Note 7)	63
BSR16 (T8)	TO-236 (49)	60	60	5	10	75 100 100 100 50	0.1 1 10 150 500	10 10 10 10 10	0.4 1.3 2.6	150 500	8	200 50		(Note 7)	63
BSR17A (U92)	TO-236 (49)	60	40	6	50	40 70 100 60 30	0.1 1 10 50 100	1 1 1 1 1	0.2 0.65 0.85	10 10	4	300 20	250	(Note 5)	23 (6-72)
BSR18A (T92)	TO-236 (49)	40	40	5	50	60 80 100 60 30	0.1 1 10 50 100	1 1 1 1 1	0.25 0.65 0.85	10 10	4.5	250 10	300	(Note 5)	66 (6-79)
BSS63 (T3)	TO-236 (49)	110	100	6	100	30 30	10 25	1 1	0.25 0.9	25		50 25			74 (6-84)
BSS64 (U3)	TO-236 (49)	120	80	5	100	20	10	1	0.15 0.2	5	60 4				16 (6-88)

NOTE: National preferred device for each process in bold. Number shown in parentheses indicates location (section-page) of device datasheet.

Pro Electron Surface Mount Bipolar Devices (continued)

Device No. (SOT-23 Mark)	Case Style	V_{CES}^*		V_{CEO} (V) Min	V_{EBO} (V) Min	I_{CES}^*		H_{FE} h_{fe} Min Max	I_C & V_{CE} (mA) (V)	$V_{CE(SAT)}$ & $V_{BE(ON)}$ (V) (V) Max Min Max		I_C (mA) Max	C_{ob} (pF) Max	f_T (MHz) Min	I_C (mA) Max	$t_{(off)}$ (ns) Max	NF (dB) Max	Test Conditions	Process No.
		V_{CB0} (V) Min	I_{CB0} (nA) Max			$V_{BE(SAT)}$ (V) Max	I_C (mA) Max												
BSS79C (CF)	TO-236 (49)	60	100	40	5	100	50	10	10	0.4 1.6	150 500	6	200	20					19
BSV52 (B2)	TO-236 (49)	20	100	12	5	100	10	1	1	0.3	50 10	4	400	10	18			(Note 4)	21 (6-92)

TEST CONDITIONS

Note 1: $I_C = 200 \mu A$, $V_{CE} = 5V$, $f = 1 \text{ kHz}$.

Note 2: $I_C = 15 \text{ mA}$, $I_B^1 = I_B^2 = 1 \text{ mA}$.

Note 3: $I_{CE} = 200 \mu A$, $V_{CE} = 5V$, $f = 200 \text{ Hz}$.

Note 4: $I_C / I_B = 3.3$.

Note 5: $I_C = 10 \text{ mA}$, $V_{CC} = 3V$, $I_B^1 = I_B^2 = 1 \text{ mA}$.

Note 6: $I_C = 100 \mu A$, $V_{CE} = 5V$, $f = 1 \text{ kHz}$.

Note 7: $I_C = 150 \text{ mA}$, $V_{CC} = 6V$, $I_B^1 = I_B^2 = 15 \text{ mA}$.

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